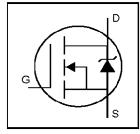
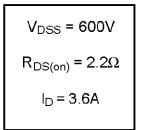


### HEXFET® Power MOSFET

- Surface Mount (IRFBC30S)
- Low-profile through-hole (IRFBC30L)
- Available in Tape & Reel (IRFBC30S)
- Dynamic dv/dt Rating
- 150°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

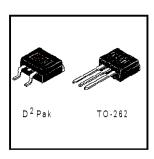




#### Description

Third generation HEXFETs from international Rectifier provide the designer with the best combination offasts witching, ruggedized device design, low on-resistance and cost-effectiveness.

The  $D^2Pak$  is a surface mount power package capable of the accommodating die sizes up to HEX-4. It provides the highest power capability and the lowest possible on-resistance in any existing surface mount package. The  $D^2Pak$  is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0W in a typical surface mount application. The through-hole version (IRFBC30L) is available for low-profile applications.



#### **Absolute Maximum Ratings**

|   | Parameter  | Max.                   | Units |  |
|---|--|------------------------|-------|--|
| I <sub>D</sub> @ T <sub>C</sub> = 25°C  | Continuous Drain Current, V <sub>GS</sub> @ 10VS | 3.6                    |       |  |
| I <sub>D</sub> @ T <sub>C</sub> = 100°C | Continuous Drain Current, V <sub>GS</sub> @ 10V® | 2.3                    | Α     |  |
| I <sub>DM</sub>                         | Pulsed Drain Current ①⑤                          | 14                     |       |  |
| P <sub>D</sub> @T <sub>A</sub> =25°C    | Power Dissipation                                | 3.1                    | W     |  |
| P <sub>D</sub> @T <sub>C</sub> = 25°C   | Power Dissipation                                | 74                     | W     |  |
|   | Linear Derating Factor                           | 0.59                   | W/°C  |  |
| V <sub>GS</sub>                         | Gate-to-Source Voltage                           | ± 20                   | V     |  |
| E <sub>AS</sub>                         | Single Pulse Avalanche Energy@®                  | 290                    | mJ    |  |
| l <sub>AR</sub>                         | Avalanche Current①                               | 3.6                    | Α     |  |
| E <sub>AR</sub>                         | Repetitive Avalanche Energy①                     | 7.4                    | mJ    |  |
| dv/dt                                   | Peak Diode Recovery dv/dt ৩©                     | 3.0                    | V/ns  |  |
| TJ                                      | Operating Junction and                           | -55 to + 150           |       |  |
| T <sub>SIG</sub>                        | Storage Temperature Range                        |                        | °C    |  |
|   | Soldering Temperature, for 10 seconds            | 300 (1.6mm from case ) |       |  |

#### Thermal Resistance

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|      | Parameter  | Тур. | Max. | Units |
|------|--|------|------|-------|
| Rejc | Junction-to-Case                                   |      | 1.7  | 00001 |
| Raja | Junction-to-Ambient ( PCB Mounted, steady-state)** |      | 40   | °C/W  |

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### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

|  | Parameter                            | Min. | Тур. | Max. | Units | Conditions   |
|--|--------------------------------------|------|------|------|-------|--|
| V <sub>(BR)DSS</sub>                   | Drain-to-Source Breakdown Voltage    | 600  |      |      | ٧     | $V_{GS} = 0V, I_{D} = 250\mu A$                    |
| ΔV <sub>(BR)DSS</sub> /ΔT <sub>J</sub> | Breakdown Voltage Temp. Coefficient  |      | 0.62 |      | V/°C  | Reference to 25°C, I <sub>□</sub> =1mA⑤            |
| R <sub>DS(on)</sub>                    | Static Drain-to-Source On-Resistance |      |      | 2.2  | Ω     | V <sub>GS</sub> =10V, I <sub>D</sub> =2.2A ④       |
| V <sub>GS(th)</sub>                    | Gate Threshold Voltage               | 2.0  |      | 4.0  | V     | $V_{DS} = V_{GS}, I_{D} = 250 \mu A$               |
| <b>g</b> fs                            | Forward Transconductance             | 2.5  |      |      | S     | V <sub>DS</sub> = 50V, I <sub>D</sub> = 2.2A⑤      |
| L                                      | Drain-to-Source Leakage Current      |      |      | 100  | μА    | V <sub>DS</sub> = 600V, V <sub>GS</sub> = 0V       |
| DSS                                    | Brain-to-oddree Leakage Current      |      |      | 500  | μΑ ]  | $V_{DS} = 480V$ , $V_{GS} = 0V$ , $T_{J} = 125$ °C |
| ı                                      | Gate-to-Source Forward Leakage       |      |      | 100  | n 4   | V <sub>GS</sub> = 20V                              |
| GSS                                    | Gate-to-Source Reverse Leakage       |      |      | -100 | nA -  | V <sub>GS</sub> = -20V                             |
| Qg                                     | Total Gate Charge                    |      |      | 31   |       | I <sub>D</sub> = 3.6A                              |
| Q <sub>gs</sub>                        | Gate-to-Source Charge                |      |      | 4.6  | nC    | V <sub>DS</sub> = 360V                             |
| Q <sub>gd</sub>                        | Gate-to-Drain ("Miller") Charge      |      |      | 17   |       | $V_{GS}$ = 10V, See Fig. 6 and 13 $\P$             |
| t <sub>d(on)</sub>                     | Turn-On Delay Time                   |      | 11   |      |       | V <sub>DD</sub> = 300V                             |
| t <sub>r</sub>                         | Rise Time                            |      | 13   |      |       | I <sub>D</sub> = 3.6A                              |
| t <sub>d(off)</sub>                    | Turn-Off Delay Time                  |      | 35   |      | ns    | $R_G = 12\Omega$                                   |
| t <sub>f</sub>                         | Fall Time                            |      | 14   |      |       | $R_{\text{D}}$ =82 $\Omega$ , See Fig. 10 $\P$     |
| L <sub>S</sub>                         | Internal Source Inductance           |      | 7.5  |      | nH    | Between lead,                                      |
|  |                                      |      |      |      |       | and center of die contact                          |
| C <sub>iss</sub>                       | Input Capacitance                    |      | 660  |      |       | V <sub>GS</sub> = 0V                               |
| Coss                                   | Output Capacitance                   |      | 86   |      | pF    | V <sub>DS</sub> = 25V                              |
| C <sub>rss</sub>                       | Reverse Transfer Capacitance         |      | 19   |      | 1     | f = 1.0MHz, See Fig. 5©                            |

### Source-Drain Ratings and Characteristics

|                 | Parameter                 | Min.  | Тур. | Max. | Units       | Conditions   |
|-----------------|---------------------------|---|------|------|-------------|--|
| Is              | Continuous Source Current |   |      | 2.0  |             | MOSFET symbol  |
|                 | (Body Diode)              |   | 3.6  | .ь А | showing the |  |
| I <sub>SM</sub> | Pulsed Source Current     |   |      | 14   |             | integral reverse                                     |
|                 | (Body Diode) ①            | de) ①   |      |      | 4           | p-n junction diode.                                  |
| V <sub>SD</sub> | Diode Forward Voltage     |   |      | 1.6  | V           | $T_J = 25^{\circ}C$ , $I_S = 3.6A$ , $V_{GS} = 0V$ ④ |
| t <sub>rr</sub> | Reverse Recovery Time     |   | 370  | 810  | ns          | T <sub>J</sub> = 25°C, I <sub>F</sub> =3.6A          |
| Qm              | Reverse Recovery Charge   |   | 2.0  | 4.2  | μC          | di/dt = 100A/µs ⊕⑤                                   |
| ton             | Forward Turn-On Time      | Intrinsic turn-on time is negligible (turn-on is dominated by $L_S+L_D$ ) |      |      |             |  |

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- V<sub>DD</sub> =50V, starting T<sub>J</sub> = 25°C, L =41mH R<sub>G</sub> = 25 $\Omega$ , I<sub>AS</sub> = 3.6A. (See Figure 12)
- ③  $I_{SD} \le 3.6A$ , di/dt  $\le 60AV\mu s$ ,  $V_{DD} \le V_{(BR)DSS}$ ,  $T_{L} \le 150^{\circ}C$
- 4 Pulse width  $\leq 3000 \mu s$ ; duty cycle  $\leq 2\%$ .
- ⑤ Uses IRFBC30 data and test conditions

<sup>\*\*</sup> When mounted on 1" square PCB (FR-4 or G-10 Material ).
For recommended footprint and soldering techniques refer to application note #AN-994.

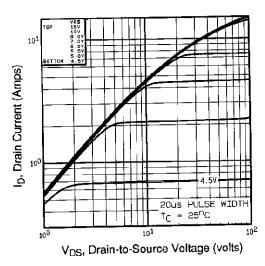


Fig 1. Typical Output Characteristics,

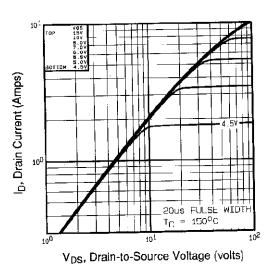


Fig 2. Typical Output Characteristics,

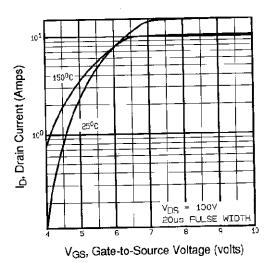


Fig 3. Typical Transfer Characteristics

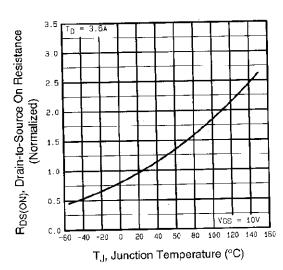


Fig 4. Normalized On-Resistance Vs. Temperature

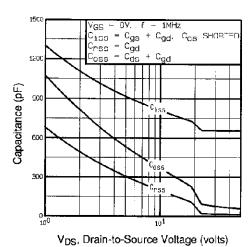


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

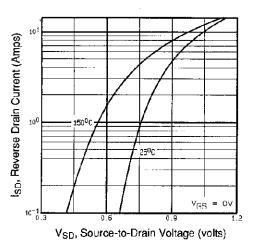


Fig 7. Typical Source-Drain Diode Forward Voltage

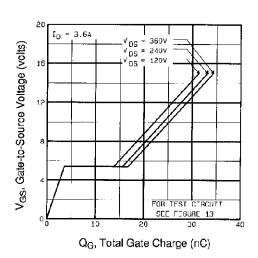


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

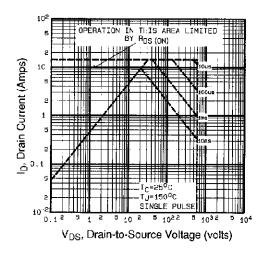


Fig 8. Maximum Safe Operating Area

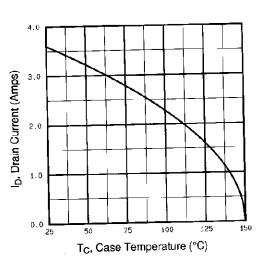


Fig 9. Maximum Drain Current Vs. Case Temperature

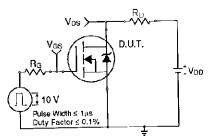


Fig 10a. Switching Time Test Circuit

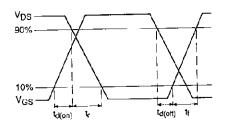


Fig 10b. Switching Time Waveforms

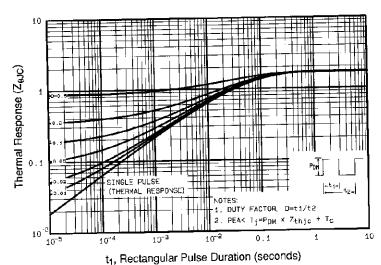


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

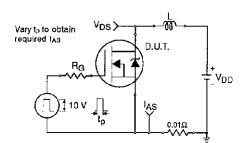


Fig 12a. Unclamped Inductive Test Circuit

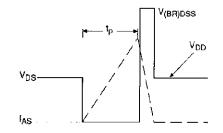


Fig 12b. Unclamped Inductive Waveforms

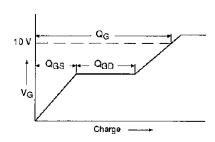


Fig 13a. Basic Gate Charge Waveform

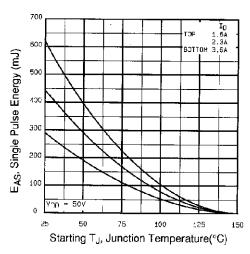


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

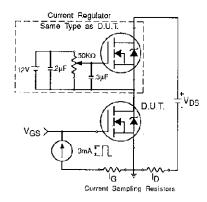
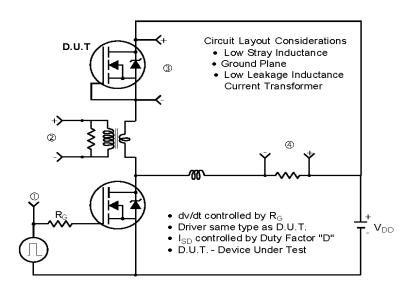


Fig 13b. Gate Charge Test Circuit

### Peak Diode Recovery dv/dt Test Circuit



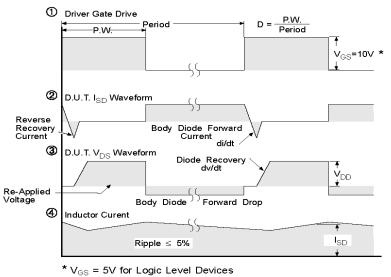
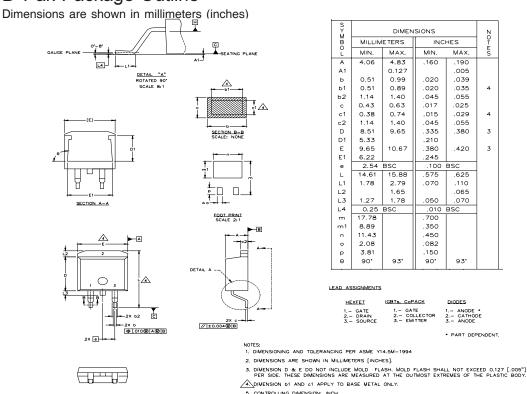


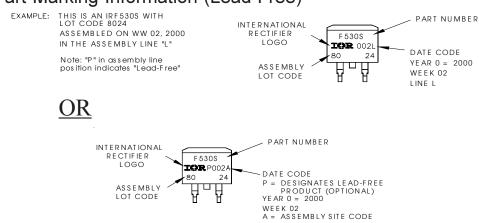
Fig 14.For N-Channel HEXFETS

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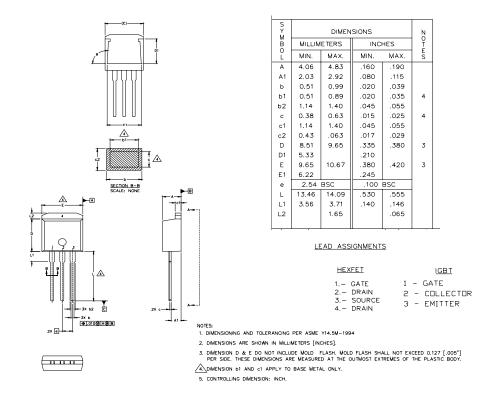
## D<sup>2</sup>Pak Package Outline



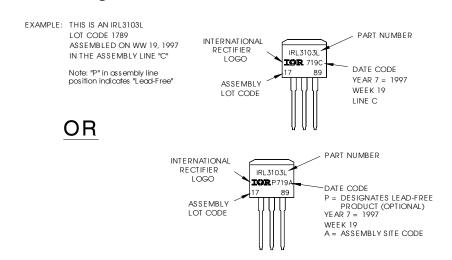
## D<sup>2</sup>Pak Part Marking Information (Lead-Free)



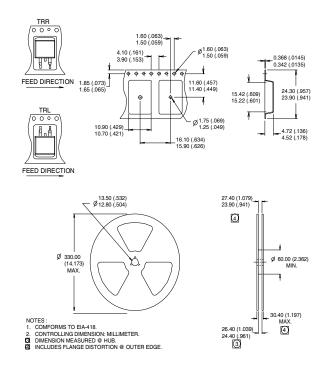
## TO-262 Package Outline



## TO-262 Part Marking Information



### D<sup>2</sup>Pak Tape & Reel Infomation



Data and specifications subject to change without notice.



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